

April 2010

FQI27N25TU_F085

250V N-Channel MOSFET

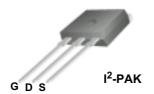
General Description

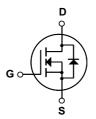
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switching DC/DC converters, switch mode power supply.

Features

- 25.5A, 250V, $R_{DS(on)} = 0.11\Omega @V_{GS} = 10 V$
- Low gate charge (typical 50 nC)
- Low Crss (typical 45 pF)
- · Fast switching
- · 100% avalanche tested
- · Improved dv/dt capability
- Qualified to AEC Q101
- · RoHS Compliant





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		Ratings	Units	
V _{DSS}	Drain-Source Voltage		250	V	
I _D	Drain Current - Continuous (T _C = 25°C) - Continuous (T _C = 100°C)		25.5	А	
			16.2	Α	
I _{DM}	Drain Current - Pulsed	(Note 1)	102	А	
V _{GSS}	Gate-Source Voltage		± 30	V	
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	600	mJ	
I _{AR}	Avalanche Current	(Note 1)	25.5	А	
E _{AR}	Repetitive Avalanche Energy	(Note 1)	18	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	5.5	V/ns	
P_{D}	Power Dissipation (T _A = 25°C) *		3.13	W	
_	Power Dissipation (T _C = 25°C)		180	W	
	- Derate above 25°C		1.43	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C	
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C	

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.7	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		40	°C/W	
R _{0JA} Thermal Resistance, Junction-to-Ambient 62.5 °C/W					
* When mount	ed on the minimum pad size recommended (PCB Mount)				

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V, I}_{D} = 250 \mu\text{A}$	250			V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		0.25		V/°C
Inee	Zero Gate Voltage Drain Current	V _{DS} = 250 V, V _{GS} = 0 V			1	μА
		V _{DS} = 200 V, T _C = 125°C			10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
On Cha	racteristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	3.0		5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 12.75 A		0.095	0.11	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 50 V, I _D = 12.75 A (Note 4)		19		S
Dynam C _{iss}	ic Characteristics Input Capacitance	\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	T	1800		pF
Coss	Output Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		350		pF
C _{rss}	Reverse Transfer Capacitance	1 - 1.0 MHZ		45		pF
	ng Characteristics					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 125 \text{ V}, I_D = 27 \text{ A},$		36		ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		164		ns
t _{d(off)}	Turn-Off Delay Time	(Note 4, 5)		81		ns
t _f Q _a	Turn-Off Fall Time			77	 6E	ns
	Total Gate Charge	$V_{DS} = 200 \text{ V}, I_D = 27 \text{ A},$		50 12.6	65	nC
Q _{gs}	Gate-Source Charge Gate-Drain Charge	V _{GS} = 10 V (Note 4, 5)		24		nC nC
Q _{gd}	Gate-Drain Ghaige	(, .,		24		110
	ource Diode Characteristics a					
I _S	Maximum Continuous Drain-Source Diode Forward Current				25.5	A
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				102	A
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 25.5 A		0.9	1.5	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_S = 27 \text{ A,}$ $dI_{C} / dt = 100 \text{ A/us} \qquad \text{(Note 4)}$		230		ns
Q _{rr}	Reverse Recovery Charge	erse Recovery Charge $dI_F / dt = 100 \text{ A/}\mu\text{s}$ (Note		1.5		μC

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 1.5mH, I_{AS} = 25.5A, V_{DD} = 50V, R_G = 25 Ω, Starting T_J = 25°C 3. I_{SD} \leq 27A, di/dt \leq 300A/μs, V_{DD} \leq BV_{DSS}, Starting T_J = 25°C 4. Pulse Test : Pulse width \leq 300μs, Duty cycle \leq 2% 5. Essentially independent of operating temperature

Typical Characteristics

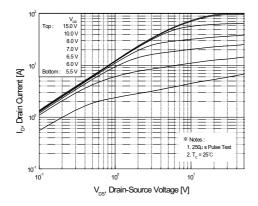


Figure 1. On-Region Characteristics

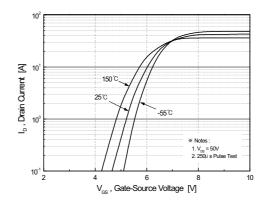


Figure 2. Transfer Characteristics

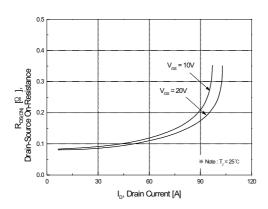


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

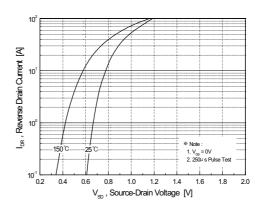


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

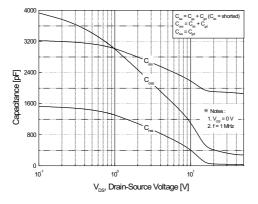


Figure 5. Capacitance Characteristics

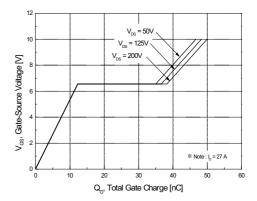


Figure 6. Gate Charge Characteristics

Typical Characteristics (Continued)

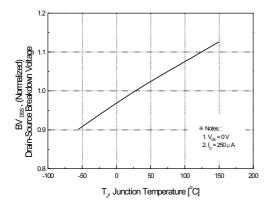
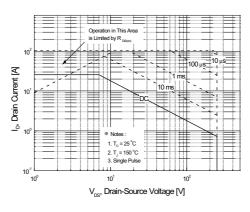


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



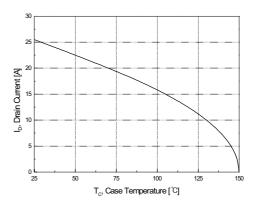


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

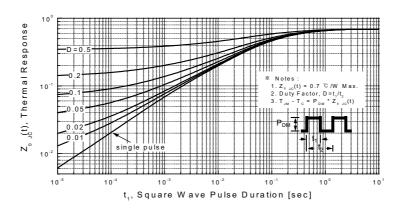
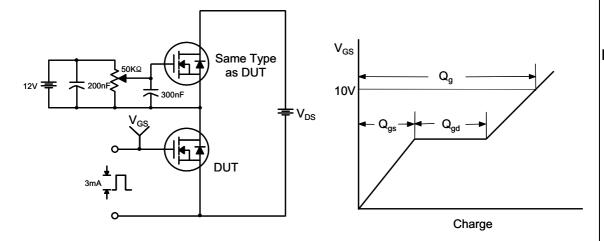
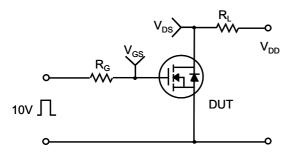


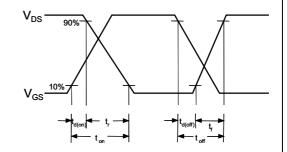
Figure 11. Transient Thermal Response Curve

Gate Charge Test Circuit & Waveform

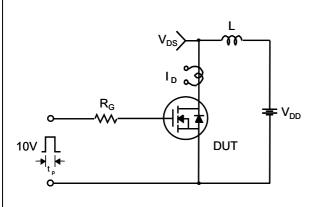


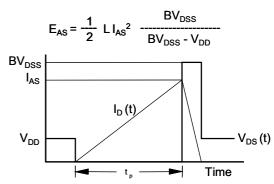
Resistive Switching Test Circuit & Waveforms



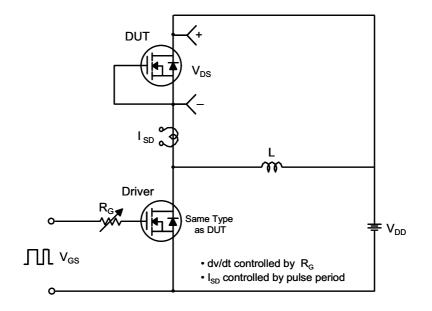


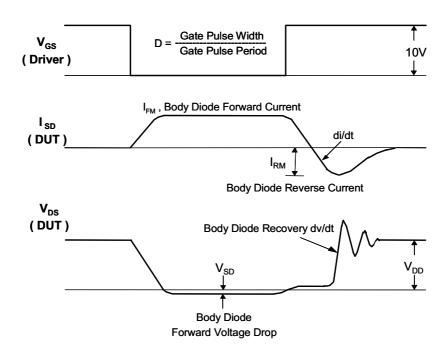
Unclamped Inductive Switching Test Circuit & Waveforms





Peak Diode Recovery dv/dt Test Circuit & Waveforms









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